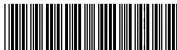


**Search Notes****Application/Control No.**

10/537,329

**Examiner**

LOIS ZHENG

**Applicant(s)/Patent under  
Reexamination**

NAKAYAMA ET AL.

**Art Unit**

1793

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventorship search	10/13/2008	LLZ
Updated EAST search	10/13/2008	LLZ